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Merjenje kakovosti električne energije v napajalnih sistemih - 2. del: Zahteve za funkcionalne preskuse in negotovost (IEC 62586-2:2017)

Power quality measurement in power supply systems - Part 2: Functional tests and uncertainty requirements (IEC 62586-2:2017)

iTeh STANDARD PREVIEW

Messung der Spannungsqualität in Energieversorgungssystemen - Teil 2: Funktionsprüfungen und Anforderungen an die Messunsicherheit (IEC 62586-2:2017)

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Mesure de la qualité de l'alimentation dans les réseaux d'alimentation - Partie 2: Essais fonctionnels et exigences d'incertitude (IEC 62586-2:2017)

Ta slovenski standard je istoveten z: EN 62586-2:2017

ICS:

17.220.20	Merjenje električnih in magnetnih veličin	Measurement of electrical and magnetic quantities
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Power quality measurement in power supply systems -
Part 2: Functional tests and uncertainty requirements
(IEC 62586-2:2017)

Mesure de la qualité de l'alimentation dans les réseaux
d'alimentation - Partie 2: Essais fonctionnels et exigences
d'incertitude
(IEC 62586-2:2017)

Messung der Spannungsqualität in
Energieversorgungssystemen - Teil 2: Funktionsprüfungen
und Anforderungen an die Messunsicherheit
(IEC 62586-2:2017)

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SIST EN 62586-2:2017

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Comité Européen de Normalisation Electrotechnique
Europäisches Komitee für Elektrotechnische Normung

CEN-CENELEC Management Centre: Avenue Marnix 17, B-1000 Brussels

EN 62586-2:2017**European foreword**

The text of document 85/525/CDV, future edition 2 of IEC 62586-2, prepared by IEC/TC 85 "Measuring equipment for electrical and electromagnetic quantities" was submitted to the IEC-CENELEC parallel vote and approved by CENELEC as EN 62586-2:2017.

The following dates are fixed:

- latest date by which the document has to be implemented at national level by publication of an identical national standard or by endorsement (dop) 2018-02-25
- latest date by which the national standards conflicting with the document have to be withdrawn (dow) 2020-08-25

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In the official version, for Bibliography, the following notes have to be added for the standards indicated:

- IEC 60359 NOTE Harmonized as EN 60359.
- IEC 61000-4-30:2008 NOTE Harmonized as EN 61000-4-30:2009¹⁾ (not modified).

¹⁾ Superseded by EN 61000-4-30:2015 (IEC 61000-4-30:2015): DOW = 2018-03-27.

Annex ZA (normative)

Normative references to international publications with their corresponding European publications

The following documents, in whole or in part, are normatively referenced in this document and are indispensable for its application. For dated references, only the edition cited applies. For undated references, the latest edition of the referenced document (including any amendments) applies.

NOTE 1 When an International Publication has been modified by common modifications, indicated by (mod), the relevant EN/HD applies.

NOTE 2 Up-to-date information on the latest versions of the European Standards listed in this annex is available here: www.cenelec.eu

<u>Publication</u>	<u>Year</u>	<u>Title</u>	<u>EN/HD</u>	<u>Year</u>
IEC 61000-2-4	-	Electromagnetic compatibility (EMC) - Part 2-4: Environment - Compatibility levels in industrial plants for low-frequency conducted disturbances	EN 61000-2-4	-
IEC 61000-4-7	-	Electromagnetic compatibility (EMC) - Part 4-7: Testing and measurement techniques - General guide on harmonics and interharmonics measurements and instrumentation, for power supply systems and equipment connected thereto	EN 61000-4-7	-
IEC 61000-4-15	-	Electromagnetic compatibility (EMC) - Part 4-15: Testing and measurement techniques - Flickermeter - Functional and design specifications	EN 61000-4-15	-
IEC 61000-4-30	2015	Electromagnetic Compatibility (EMC) - Part 4-30: Testing and measurement techniques - Power quality measurement methods	EN 61000-4-30	2015
IEC 62586-1	2013	Power quality measurement in power supply systems - Part 1: Power Quality Instruments (PQI)	EN 62586-1	2014
ISO/IEC Guide 98-3 2008		Uncertainty of measurement - Part 3: Guide to the expression of uncertainty in measurement (GUM:1995)	-	-

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**Power quality measurement in power supply systems –
Part 2: Functional tests and uncertainty requirements**

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INTERNATIONAL ELECTROTECHNICAL COMMISSION

POWER QUALITY MEASUREMENT IN POWER SUPPLY SYSTEMS –**Part 2: Functional tests and uncertainty requirements**

FOREWORD

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International Standard IEC 62586-2 has been prepared by IEC technical committee 85: Measuring equipment for electrical and electromagnetic quantities.

This second edition cancels and replaces the first edition published in 2013. This edition constitutes a technical revision.

This edition includes the following significant technical changes with respect to the previous edition:

- a) test procedures for RVC and current have been added;
- b) mistakes have been fixed.